

RELIABILITY MONITOR

DS1000M-100 OCT '99 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1000	E3	9944	DH927108AJC	8	PDIP	300	CPS (ChipPac, China)
PROCESS Single Poly, Single Metal 1.2 µm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: Tuse:
Ea: Vuse:
β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24791	INFANT LIFE	125C, 7.0 VOLTS	234	48	HOUR	2
24792	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
		TOTAL:	103	DEVICE HRS: 3.01E+07		2
24793	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
24794	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
		TOTAL:				0
24795	AUTOCLAVE	121C STEAM, UNBIASED	37	96	HOUR	0
		TOTAL:				0
JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION			
24791	1-SHORTS, 1-AC	IN PROCESS	IN PROCESS			

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1000M-100 JAN '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1000	E3	2	DH938700ABB 8	PDIP	300	CPS (ChipPac, China	
PROCESS Single Poly, Single Metal 1.2 µm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: Tuse:
Ea: Vuse:
β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25000	INFANT LIFE	125C, 7.0 VOLTS	234	48	HOUR	0
25001	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
		TOTAL:	30	DEVICE HRS: 3.08E+07		0
25002	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
25003	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
		TOTAL:				0
25004	AUTOCLAVE	121C STEAM, UNBIASED	40	96	HOUR	0
		TOTAL:				0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1000M-100 APR '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1000	E3	9	DH949661AEA	8	PDIP	300	CPS (ChipPac, China)
PROCESS Single Poly, Single Metal 1.2 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25406	INFANT LIFE	125C, 7.0 VOLTS	234	48	HOUR	0
25407	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
TOTAL:			71	DEVICE HRS: 1.30E+07		0
25408	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
TOTAL:			40	1000	CYCL	0
25409	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
TOTAL:						0
25410	AUTOCLAVE	121C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1232L APR '99 MONITOR-CHIPPAC,KOREA

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1232	C2-L	9848	DL829603AAC	8	SOIC	150	CPK (ChipPac, Korea)
PROCESS Single Poly, Single Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24189	INFANT LIFE	125C, 7.0 VOLTS	234	48	HOUR	0
24190	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
		TOTAL:	30	DEVICE HRS: 3.05E+07		0
23660	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
23661	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	0
	CONVECTION REFLOW	235C	238	3	PASS	0
		TOTAL:				0
24188	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
24191	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
24192	HAST	130C, 85%R.H.,5.5V	77	100	HOUR	0
		TOTAL:				0
24193	AUTOCLAVE	121C STEAM, UNBIASED	36	96	HOUR	0
		TOTAL:				0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1232L JAN '00 Monitor

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1232	C2-L	9948	DK933191AAJ	8	SOIC	150	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25022	INFANT LIFE	125C, 7.0 VOLTS	234	48	HOUR	
		TOTAL:		FAIL RATE (Fits):		DEVICE HRS: 3.92E+06
25019	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
25020	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
		TOTAL:				0
25021	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1233Z-10 APR '99 MONITOR-CARSEM

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1233	A5	9911	DM837033ABA	3	SOT223	140	Carsem
PROCESS Single Poly, Single Metal 1.2 μm Zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23773	INFANT LIFE	125C, 7.0 VOLTS	229	48	HOUR	0
23939	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
		TOTAL:	30	FAIL RATE (Fits): DEVICE HRS: 3.07E+07		0
23662	ULTRASOUND	J-STD-020	4			0
	EXTERNAL VISUAL	MIL-STD-883-2009	4			0
		TOTAL:				0
23663	STORAGE LIFE	125C	233	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	233	168	HOUR	
	CONVECTION REFLOW	235C	233	3	PASS	0
		TOTAL:				0
23772	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
23940	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
23941	HAST	130C, 85%R.H.,5.5V	72	100	HOUR	0
		TOTAL:				0
23942	AUTOCLAVE	121C STEAM, UNBIASED	40	96	HOUR	0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1233Z-10 APR '99 MONITOR-CARSEM

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1233	A5	9911	DM837033ABA	3	SOT223	140	Carsem
PROCESS Single Poly, Single Metal 1.2 μm Zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stess

RELIABILITY MONITOR

DS1233Z-10 JAN '00 Monitor

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1233	A5	9952	DM929359ABA 3	SOT223	140	Carsem	
PROCESS Single Poly, Single Metal 1.2 μm Zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25036	INFANT LIFE	125C, 7.0 VOLTS	229	48	HOUR	0
25037	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	
		TOTAL:	30	DEVICE HRS: 3.07E+07		0
25033	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
25034	STORAGE LIFE	125C	233	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	233	168	HOUR	
	CONVECTION REFLOW	235C	233	3	PASS	0
		TOTAL:				0
25035	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
25038	TEMP CYCLE	-55C TO 125C	40	700	CYCL	
		TOTAL:				
25039	HAST	130C, 85%R.H.,5.5V	72	100	HOUR	0
		TOTAL:				0
25040	AUTOCLAVE	121C STEAM, UNBIASED	40	96	HOUR	0
		TOTAL:				0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1267-10 AUG '99 MONITOR - ANAM,PI

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS PACKAGE	WIDTH	ASSEMBLY SITE
DS1267	A1	9823	DK807766AAE- 20	TSSOP	173	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 1.2 µm Poly1 Resistor						

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24343	INFANT LIFE	125C, 6.0 V, -4.0V	228	48	HOUR	0
24344	HIGH VOLTAGE LIFE	125C, 6.0 V, -4.0V	77	336	HOUR	0
		125C, 6.0 V, -4.0V	77	1000	HOUR	0
		TOTAL:	87	FAIL RATE (Fits): DEVICE HRS: 1.05E+07		0
24340	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
24341	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	0
	CONVECTION REFLOW	235C	238	3	PASS	0
		TOTAL:				0
24342	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
24345	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
24346	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
		TOTAL:				0
24347	AUTOCLAVE	121C STEAM, UNBIASED	34	96	HOUR	0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1267-10 AUG '99 MONITOR - ANAM,PI

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1267	A1	9823	DK807766AAE-	20	TSSOP	173	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 1.2 μ m Poly1 Resistor							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β :	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stess

RELIABILITY MONITOR

DS1302 MAR '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1302	A3	6	DH945115AAB	8	PDIP	300	CPS (ChipPac, China)
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25211	INFANT LIFE	125C, 6.0 VOLTS	234	48	HOUR	1
25212	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
TOTAL:			429	DEVICE HRS: 4.72E+06		1
25213	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
25214	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
TOTAL:						0
25215	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	39	96	HOUR	0
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1302 JUN '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1302	A3	18	DH008331AAA	8	PDIP	300	CPS (ChipPac, China
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25535	INFANT LIFE	125C, 6.0 VOLTS	234	48	HOUR	0
TOTAL:			FAIL RATE (Fits):	635	DEVICE HRS: 1.44E+06	0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1621S JUN '99 MONITOR - ANAM,PI

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1621	A7	9915	DK815282AAB	8	SOIC	150	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 0.8 μm E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24321	INFANT LIFE	125C, 7.0 VOLTS	237	48	HOUR	0
24322	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
		TOTAL:	30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
24314	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
24315	STORAGE LIFE	125C	241	24	HOUR	0
	MOISTURE SOAK	85C/85% R.H.	241	168	HOUR	0
	CONVECTION REFLOW	235C	241	3	PASS	0
		TOTAL:				0
24316	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
24323	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
24324	BIASED MOISTURE	85/85, 5.5 VOLTS	70	274	HOUR	0
			70	959	HOUR	0
		TOTAL:				0
24325	WRITE CYCLE STRESS	85 C, 7.0 VOLTS	47	50	KCYC	0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1621S JUN '99 MONITOR - ANAM,PI

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1621	A7	9915	DK815282AAB	8	SOIC	150	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 0.8 μm E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
		TOTAL:				0
24326	STORAGE LIFE	150C	45	336	HOUR	1
			45	1000	HOUR	0
		TOTAL:				1
JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION			
24326	DATA RETENTION	IN VERIFICATION	NA			

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS17485 AUG '99 MONITOR,D.P-ANAM,PI.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS17485	A4-5	9906	DK838211AAF	24	SOIC	300	ATP (Anam, PI)
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24362	INFANT LIFE	125C, 7.0 VOLTS	231	48	HOUR	0
24363	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	1
		125C, 7.0 VOLTS	76	1000	HOUR	0
		TOTAL:	66	DEVICE HRS: 3.04E+07		1
24359	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
24360	STORAGE LIFE	125C	237	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	237	144	HOUR	
	CONVECTION REFLOW	235C	237	3	PASS	0
		TOTAL:				0
24361	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
24364	TEMP CYCLE	-55C TO 125C	50	300	CYCL	0
			50	1000	CYCL	0
		TOTAL:				0
24365	HAST	130C, 85%R.H.,5.5V	66	100	HOUR	
		TOTAL:				
24366	AUTOCLAVE	121C STEAM, UNBIASED	38	96	HOUR	
		TOTAL:				

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS17485 AUG '99 MONITOR,D.P-ANAM,PI.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS17485	A4-5	9906	DK838211AAF	24	SOIC	300	ATP (Anam, PI)
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
JOB NO	FAILURE MODE	FAILURE MECHANISM				
24363	IBBRAM ZERO	IN PROCESS				NA
24363	IBBRAM_ZERO	IN VERIFICATION				NA

Empty "No of Fails" TOTAL implies that Material is still in stess

RELIABILITY MONITOR

DS1803-010 NOV '98 MONITOR - HYUNDAI,K.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	9833	DL820412AAB	16	SOIC	150	CPK (ChipPac, Korea
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23173	INFANT LIFE	125C, 7.0 VOLTS	234	48	HOUR	0
23923	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
		TOTAL:	30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
22797	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
22798	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	0
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
		TOTAL:				0
23172	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
23924	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
23925	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
		TOTAL:				0
23926	AUTOCLAVE	121C STEAM, UNBIASED	40	96	HOUR	0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1803-010 NOV '98 MONITOR - HYUNDAI,K.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	9833	DL820412AAB	16	SOIC	150	CPK (ChipPac, Korea
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stess

RELIABILITY MONITOR

DS1803-010 FEB '99 MONITOR - HYUNDAI,K.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	9835	DL818111AAB	16	SOIC	150	CPK (ChipPac, Korea
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
23928	INFANT LIFE	125C, 7.0 VOLTS	234	48	HOUR	0
24003	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	1
		125C, 7.0 VOLTS	76	1000	HOUR	0
		TOTAL:	66	DEVICE HRS: 3.04E+07		1
23274	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
23275	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
		TOTAL:				0
23927	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
24004	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
24005	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
		TOTAL:				0
24006	AUTOCLAVE	121C STEAM, UNBIASED	38	96	HOUR	1

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1803-010 FEB '99 MONITOR - HYUNDAI,K.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	9835	DL818111AAB	16	SOIC	150	CPK (ChipPac, Korea
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						1
JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION			
24003	CONTINUITY	EOS	NA			
24006	CONTINUITY	NO FURTHER ANALYSIS	NA			

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1803-010 AUG '99 MONITOR -ANAM,PI.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	9909	DK830515AAB	16	SOIC	150	ATP (Anam, PI)
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24370	INFANT LIFE	125C, 7.0 VOLTS	234	48	HOUR	0
24371	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
		TOTAL:	30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
24367	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
24368	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	0
	CONVECTION REFLOW	235C	238	3	PASS	0
		TOTAL:				0
24369	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
24372	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
24373	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
		TOTAL:				0
24374	AUTOCLAVE	121C STEAM, UNBIASED	38	96	HOUR	0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1803-010 AUG '99 MONITOR -ANAM,PI.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	9909	DK830515AAB	16	SOIC	150	ATP (Anam, PI)
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stess

RELIABILITY MONITOR

DS1803-010 NOV '99 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	9923	DK913631AAA	16	SOIC	150	ATP (Anam, PI)
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24738	INFANT LIFE	125C, 7.0 VOLTS	224	48	HOUR	0
24739	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
		TOTAL:	30	FAIL RATE (Fits): DEVICE HRS: 3.07E+07		0
24735	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
24736	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
		TOTAL:				0
24737	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
24740	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	2
		TOTAL:				2
24741	BIASED MOISTURE	85/85, 5.5 VOLTS	67	274	HOUR	0
			67	959	HOUR	0
		TOTAL:				0
24742	AUTOCLAVE	121C STEAM, UNBIASED	40	96	HOUR	0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1803-010 NOV '99 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	9923	DK913631AAA	16	SOIC	150	ATP (Anam, PI)
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						0
JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION			
24740	CONTINUITY	IN PROCESS	NA			

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1869 SEP '99 MONITOR - NSEB

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1869	A3	9907	DJ824247ABA	8	SOIC	208	NSEB
PROCESS Single Poly, Single Metal 1.2 μm E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24441	INFANT LIFE	125C, 7.0 VOLTS	231	48	HOUR	0
24442	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	75	336	HOUR	0
		125C, 7.0 VOLTS	75	1000	HOUR	0
		TOTAL:	31	FAIL RATE (Fits): DEVICE HRS: 2.95E+07		0
24438	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
24439	STORAGE LIFE	125C	241	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	241	168	HOUR	
	CONVECTION REFLOW	235C	241	3	PASS	0
		TOTAL:				0
24440	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
24443	TEMP CYCLE	-55C TO 125C	38	300	CYCL	0
			38	1000	CYCL	0
		TOTAL:				0
24444	BIASED MOISTURE	85/85, 5.5 VOLTS	54	274	HOUR	0
			54	959	HOUR	0
		TOTAL:				0
24445	WRITE CYCLE STRESS	85 C, 7.0 VOLTS	46	25	KCYC	0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS1869 SEP '99 MONITOR - NSEB

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1869	A3	9907	DJ824247ABA	8	SOIC	208	NSEB
PROCESS Single Poly, Single Metal 1.2 μ m E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β :	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
		TOTAL:				0
24446	STORAGE LIFE	150C	46	336	HOUR	0
			46	1000	HOUR	0
		TOTAL:				0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2108 FEB '00 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2108	B7	9951	DK940069AAC	24	SOIC	300	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 5.0 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25106	INFANT LIFE	125C, 6.0 VOLTS	234	48	HOUR	2
25107	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	77	1000	HOUR	0
		TOTAL:	278	FAIL RATE (Fits): DEVICE HRS: 1.12E+07		2
25103	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
25104	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	238	144	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
		TOTAL:				0
25105	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
25108	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1200	CYCL	0
		TOTAL:				0
25109	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
		TOTAL:				0
25110	AUTOCLAVE	121C STEAM, UNBIASED	35	96	HOUR	0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2108 FEB '00 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2108	B7	9951	DK940069AAC	24	SOIC	300	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 5.0 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						0
JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION			
25106	RESISTANCE	LEAKAGE HI ON PIN 5	NO FURTHER ACTION			

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2109 DEC '99 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2109	A7	9842	DM812689AAA	28	SOIC	300	Carsem
PROCESS Single Poly, Single Metal 0.8 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24808	INFANT LIFE	125C, 7.0 VOLTS	232	48	HOUR	2
24809	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	
TOTAL:			241	DEVICE HRS: 1.29E+07		2
24805	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
24806	STORAGE LIFE	125C	237	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	237	168	HOUR	
	CONVECTION REFLOW	235C	237	3	PASS	0
TOTAL:						0
24807	PRECONDITION U/S	J-STD-020	4			1
TOTAL:						1
24810	TEMP CYCLE	-55C TO 125C	50	300	CYCL	
TOTAL:						
24811	HAST	130C, 85%R.H.,5.5V	66	100	HOUR	
TOTAL:						
24812	AUTOCLAVE	121C STEAM, UNBIASED	38	96	HOUR	0
TOTAL:						0
JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION			
24807	DIE DELAMINATION	ONE SAMPLE W/100% DIE	NONE, 237 PRODUCTS WERE			

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2109 DEC '99 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2109	A7	9842	DM812689AAA	28	SOIC	300	Carsem
PROCESS Single Poly, Single Metal 0.8 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
		DELAM/ELECTRICALLY GOOD				
			PRECONDITIONED TO LEVEL ONE W/NO FAILURES. SUBSEQUENT STRESSING IN PROCESS.			
24808	TERM RESISTANCE	GATE OXIDE				
			SEVERAL EVALUATIONS ARE IN PROCESS TO IMPROVE GATE OXIDE PERFORMANCE			

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2118M MAR '00 MONITOR, D.P. Anam,K.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2118M	B1	5	ZN946350AAG	36	SSOP	300	ASI (Anam, K)
PROCESS Single Poly, Single Metal 0.6 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25233	INFANT LIFE	125C, 6.0 VOLTS	234	48	HOUR	0
25234	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	75	336	HOUR	0
		125C, 6.0 VOLTS	75	1000	HOUR	0
		TOTAL:	84	DEVICE HRS: 1.08E+07		0
25230	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
25231	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	30C/60% R.H.	238	240	HOUR	0
	CONVECTION REFLOW	235C	238	3	PASS	0
		TOTAL:				0
25232	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
25235	TEMP CYCLE	-55C TO 125C	35	300	CYCL	0
		TOTAL:				0
25237	AUTOCLAVE	121C STEAM, UNBIASED	32	96	HOUR	0
		TOTAL:				0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2154 MAR '00 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2154	A2	7	DK948587AAA	100	LQFP	550	ATP (Anam, PI)
PROCESS Double Poly, Double Met 0.8 μm N Depletion Capacitor							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25241	INFANT LIFE	125C, 7.0 VOLTS	234	48	HOUR	1
25242	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	90	336	HOUR	0
		125C, 7.0 VOLTS	90	1000	HOUR	
		TOTAL:	57	FAIL RATE (Fits): DEVICE HRS: 3.53E+07		1
25238	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
25239	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	238	240	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
		TOTAL:				0
25240	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
25243	TEMP CYCLE	-55C TO 125C	66	300	CYCL	0
		TOTAL:				0
25244	HAST, NO BIAS	130C, 85% R.H.	77	200	HOUR	0
		TOTAL:				0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2175 JAN '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2175	D1	1	DK941179AAD	16	SOIC	300	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 2.0 μm Pfield							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25044	INFANT LIFE	125C, 7.0 VOLTS	234	48	HOUR	0
25045	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
		TOTAL:	30	DEVICE HRS: 3.08E+07		0
25041	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
25042	TEMP CYCLE	-55C TO 125C	238	10	CYCL	
	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
		TOTAL:				0
25043	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
25046	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1100	CYCL	0
		TOTAL:				0
25047	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
		TOTAL:				0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2175 JAN '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2175	D1	1	DK941179AAD	16	SOIC	300	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 2.0 μm Pfield							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25048	AUTOCLAVE	121C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS21S07 NOV '99 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS21S07	C1-A	9908	DK836680AAF	20	TSSOP	173	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 0.8 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24730	INFANT LIFE	125C, 7.0 VOLTS	231	48	HOUR	0
24731	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
		TOTAL:	30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
24727	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
24728	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	0
	CONVECTION REFLOW	235C	238	3	PASS	0
		TOTAL:				0
24729	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
24732	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
24733	BIASED MOISTURE	85/85, 5.5 VOLTS	74	274	HOUR	0
			74	959	HOUR	0
		TOTAL:				0
24734	AUTOCLAVE	121C STEAM, UNBIASED	40	96	HOUR	0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS21S07 NOV '99 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS21S07	C1-A	9908	DK836680AAF	20	TSSOP	173	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 0.8 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stess

RELIABILITY MONITOR

DS21S07 FEB '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS21S07	C1-A	9937	DK926747AAP	20	TSSOP	173	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 0.8 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25098	INFANT LIFE	125C, 7.0 VOLTS	234	48	HOUR	0
25099	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	1
TOTAL:			158	DEVICE HRS: 1.28E+07		1
25095	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
25096	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
TOTAL:						0
25097	PRECONDITION U/S	J-STD-020	4			0
TOTAL:						0
25100	TEMP CYCLE	-55C TO 125C	38	300	CYCL	0
TOTAL:						0
25101	BIASED MOISTURE	85/85, 5.5 VOLTS	76	274	HOUR	0
TOTAL:						0
25102	AUTOCLAVE	121C STEAM, UNBIASED	38	96	HOUR	0
TOTAL:						0
JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION			
25099	ACTIVE NEGATION	IN PROCESS	NA			

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS21S07 MAY '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS21S07	C1-A	13	DM002285AAF	20	TSSOP	173	Carsem S
PROCESS Single Poly, Single Metal 0.8 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25446	INFANT LIFE	125C, 7.0 VOLTS	234	48	HOUR	
		TOTAL:		FAIL RATE (Fits):	DEVICE HRS: 3.92E+06	
25443	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
25444	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
		TOTAL:				0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2401 MAR '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2401	C2	7	DA925802AJA	3	TO92	180	Fastech
PROCESS Single Poly, Single Metal 0.6 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25245	INFANT LIFE	125C, 6.0 VOLTS	234	48	HOUR	0
25246	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	77	1000	HOUR	0
TOTAL:			81	DEVICE HRS: 1.13E+07		0
25247	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
25248	HAST	130C, 85%R.H.,5.5V	77	100	HOUR	0
TOTAL:						0
25249	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2401 JUN '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2401	C2	22	DA952309AKA	3	TO92	180	Fastech
PROCESS Single Poly, Single Metal 0.6 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25560	INFANT LIFE	125C, 6.0 VOLTS	234	48	HOUR	
		TOTAL:	FAIL RATE (Fits):	DEVICE HRS: 1.44E+06		

Empty "No of Fails" TOTAL implies that Material is still in stess

RELIABILITY MONITOR

DS2434 FEB '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2434	D1	1	DM831669AAA 3	3	TO226 (PR35)	350	Carsem
PROCESS Single Poly, Single Metal 0.8 μm E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25111	INFANT LIFE	125C, 7.0 VOLTS	237	48	HOUR	1
25112	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
		TOTAL:	FAIL RATE (Fits): 66	DEVICE HRS: 3.09E+07		1
25113	TEMP CYCLE	-55C TO 125C	50	300	CYCL	0
			50	1000	CYCL	0
		TOTAL:				0
25114	HAST	130C, 85%R.H.,5.5V	70	100	HOUR	0
		TOTAL:				0
25115	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	39	96	HOUR	0
		TOTAL:				0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2502 JUN '99 MONITOR - CARSEM

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2502	C2	9915	DM846764AAA	8	SOIC	150	Carsem S
PROCESS Double Poly, Single Metal 0.6 μm EPROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24169	INFANT LIFE	125C, 6.0 VOLTS	234	48	HOUR	0
24174	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	77	1000	HOUR	0
		TOTAL:	81	FAIL RATE (Fits): DEVICE HRS: 1.13E+07		0
23957	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
23958	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	0
	VAPOR PHASE REFLOW	217C	238	3	PASS	0
		TOTAL:				0
24168	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
24175	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
24176	BIASED MOISTURE	85/85, 5.5 VOLTS	75	274	HOUR	0
			75	959	HOUR	0
		TOTAL:				0
24177	STORAGE LIFE	150C	37	336	HOUR	0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2502 JUN '99 MONITOR - CARSEM

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2502	C2	9915	DM846764AAA	8	SOIC	150	Carsem S
PROCESS Double Poly, Single Metal 0.6 μm EPROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
			37	1000	HOUR	0
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2502 SEP '99 MONITOR-CARSEM

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2502	C2	9918	DM849359ACA	8	SOIC	150	Carsem S
PROCESS Double Poly, Single Metal 0.6 μm EPROM process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24480	INFANT LIFE	125C, 6.0 VOLTS	232	48	HOUR	0
24481	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	77	1000	HOUR	0
		TOTAL:	81	FAIL RATE (Fits): DEVICE HRS: 1.13E+07		0
24477	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
24478	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	0
	CONVECTION REFLOW	235C	238	3	PASS	0
		TOTAL:				0
24479	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
24482	TEMP CYCLE	-55C TO 125C	43	300	CYCL	0
			43	1000	CYCL	0
		TOTAL:				0
24483	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
		TOTAL:				0
24484	STORAGE LIFE	150C	34	336	HOUR	0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2502 SEP '99 MONITOR-CARSEM

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2502	C2	9918	DM849359ACA	8	SOIC	150	Carsem S
PROCESS Double Poly, Single Metal 0.6 μm EPROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
			34	1000	HOUR	0
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2502 JAN '00 MONITOR

DEVICE	REVISIO	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2502	C3	9930	DH917304BAA	6	TSOC	150	CPS (ChipPac, China)

JOB_NO	DESCRIPTION	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25050	STORAGE LIFE	125C	151	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	151	168	HOUR	
	CONVECTION REFLOW	235C	151	3	PASS	0
	TOTAL:					0
25051	PRECONDITION U/S	J-STD-020	4			0
	TOTAL:					0
25052	TEMP CYCLE	-55C TO 125C	77	300	CYCL	0
		-55C TO 125C	77	1000	CYCL	0
	TOTAL:					0
25053	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	66	96	HOUR	0
	TOTAL:					0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS2502 MAR '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2502	C3	5	DM941226AAB 8	8	SOIC	150	Carsem S
PROCESS Double Poly, Single Metal 0.6 μm EPROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25253	INFANT LIFE	125C, 6.0 VOLTS	232	48	HOUR	
TOTAL:				FAIL RATE (Fits):		DEVICE HRS: 1.43E+06
25250	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
25251	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
TOTAL:						0
25252	PRECONDITION U/S	J-STD-020	4			0
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS80C320 OCT '99 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS80C320	C5	9938	DH925592AAB	40	PDIP	600	CPS (ChipPac, China)
PROCESS Single Poly, Single Metal 0.6 μm Poly 1 Silicide							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24584	INFANT LIFE	125C, 7.0 VOLTS	234	48	HOUR	0
24585	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
		TOTAL:	30	DEVICE HRS: 3.05E+07		0
24586	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
24587	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
		TOTAL:				0
24588	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	40	96	HOUR	1
		TOTAL:				1
JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION			
24588	CONTINUITY	NOT ANALYZED	NA			

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS80C320 JAN '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS80C320	C5	1	DH928322BAA	40	PDIP	600	CPS (ChipPac, China)
PROCESS Single Poly, Single Metal 0.6 μm Poly 1 Silicide							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25014	INFANT LIFE	125C, 7.0 VOLTS	234	48	HOUR	0
25015	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	
		TOTAL:	30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
25016	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	
		TOTAL:				0
25017	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	
		TOTAL:				0
25018	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	40	96	HOUR	0
		TOTAL:				0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS87C520 NOV '99 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS87C520	A14	9931	DN901118AAB	44	LCC	650	ASI (Anam, K)
PROCESS Double Poly, Single Metal 0.8 μm EPROM w/silicided poly(s)							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24800	INFANT LIFE	125C, 7.0 VOLTS	219	48	HOUR	0
		125C, 7.0 VOLTS	219	48	HOUR	0
24801	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
TOTAL:			15	FAIL RATE (Fits):		0
			DEVICE HRS: 6.11E+07			
24797	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
24798	STORAGE LIFE	125C	226	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	226	240	HOUR	
	VAPOR PHASE REFLOW	217C	226	3	PASS	2
TOTAL:						2
24799	PRECONDITION U/S	J-STD-020	4			0
TOTAL:						0
24802	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS87C520 NOV '99 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS87C520	A14	9931	DN901118AAB	44	LCC	650	ASI (Anam, K)
PROCESS Double Poly, Single Metal 0.8 μm EPROM w/silicided poly(s)							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24803	HAST	130C, 85%R.H.,5.5V	56	100	HOUR	0
		TOTAL:				0
24804	STORAGE LIFE	150C	43	336	HOUR	0
			43	1000	HOUR	0
		TOTAL:				0
JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION			
24798	OP40 (2)	DESIGN CHANGE	FIXED WITH REV A15			
24798	EPROM	IN VERIFICATION	NA			

Empty "No of Fails" TOTAL implies that Material is still in stress

RELIABILITY MONITOR

DS87C520 FEB '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS87C520	A14	4	DK935356AAB	44	LCC	650	ATP (Anam, PI)
PROCESS Double Poly, Single Metal 0.8 μm EPROM w/silicided poly(s)							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25120	INFANT LIFE	125C, 7.0 VOLTS	228	48	HOUR	
		125C, 7.0 VOLTS	228	48	HOUR	
		TOTAL:				FAIL RATE (Fits):
25117	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
25118	STORAGE LIFE MOISTURE SOAK VAPOR PHASE REFLOW	125C	234	24	HOUR	
		30C/60% R.H.	234	240	HOUR	
		217C	234	3	PASS	1
		TOTAL:				1

Empty "No of Fails" TOTAL implies that Material is still in stress